

2018年度発表

主発表者	所属	発表先	タイトル	課題番号
Atsushi Iizuka	東北大学	Materials Transactions Vol.59 No.5 (2018), 843-849	Scorodite Synthesis in As(V)-Containing Fe(II) Solution in the Presence of Hematite as a Fe(III) Source	1611103PT
Toshihiro Okajima	青山学院大学	Materials Express Research, 5 (2018), 046412	Geometric structure of Sn dopants in sputtered TiO ₂ film revealed by x-ray absorption spectroscopy and first-principles DFT calculations	1504023F
Hiroshi Uemachi	関西学院大学	Electrochimica Acta, 281 (2018), 99-108	X-ray absorption near edge structure analysis of the charge-discharge mechanisms of dithiobiuret polymer used as a high-capacity cathode material for lithium-ion batteries	1011112GT
Kazuya Miura	スズキ株式会社	e-Journal of Surface Science and Nanotechnology, Vol.16 (2018), 209-213	DFT Study for Supported Pt Catalysts Focusing on the Chemical Potential	1705030G
Yi Liu	九州大学	Polymer Journal, 51 (2018),189-198	Smectic Ordered Structure and Water Repellency of a Poly(fluoroalkyl acrylate) with a Carbamate Linker	1612115F 1707063F
Hirotaaka Yamaguchia	産業技術総合研究所	Journal of Applied Crystallography, 51 (2018), 1372-1377	Stacking faults in β -Ga ₂ O ₃ crystals observed by X-ray topography	1707054G
Satoshi Masuya	佐賀大学大学院	Diamond & Related Materials, 90 (2018), 40-46	Dislocations in chemical vapor deposition (111) single crystal diamond observed by synchrotron X-ray topography and their relation with etch pits	1605029S 1607059S 1609075S 1610092S 1612119S 1601143S 1702003S 1703011S 1704021S 1706047S 1707079S
Mohamed Egiza	九州大学大学院	Coatings, 8 (2018), 359	Effects of Air Exposure on Hard and Soft X-ray Photoemission Spectra of Ultrananocrystalline Diamond/Amorphous Carbon Composite Films	1410105S 1508064S 1607062S 1610090S
Hiroto Nishihara	大阪産業技術研究所	Journal of Materials Chemistry A, 6 (2018), 12523-12531	Enhanced hydrogen chemisorption and spillover on non-metallic nickel subnanoclusters	1508068S
二宮翔	九州大学大学院	鉄と鋼, Vol. 104 No.11 (2018), 628-633	軟X線吸収分光法によるフェライト鋼中微量固溶炭素の化学状態観察	1601149S 1705026Pi 1707068F

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R. Ohtani	九州大学大学院	Inorganic Chemistry, 57 (2018), 11588–11596	Positive and negative two-dimensional thermal expansions via relaxation of node distortions	1606042F
R. Ohtani	九州大学大学院	Dalton Transactions, 48 (2018), 7198–7202	Consecutive oxidative additions of iodine on undulating 2D coordination polymers: formation of I–Pt–I chains and	1606042F
Akihiko Toda	山口大学大学院	Polymer, 169 (2019), 11–20	Crystallization and melting behaviors of poly(vinylidene fluoride) examined by fast-scan calorimetry: Hoffman–Weeks, Gibbs–Thomson and thermal Gibbs–Thomson plots	1604027A 1702008A
Naoto Nishiyama	山口大学大学院	Catalysis Science & Technology, 8 (2018), 4726–4733	Factors affecting photocatalytic activity of visible light-responsive titanium dioxide doped with chromium ions	1607058R
A. Kitajou	山口大学	J. Power Sources, 419 (2019),1–5	Electrochemical properties of titanium fluoride with high rate capability for lithium-ion batteries	1607055R
S.Shikata	関西学院大学	Japanese Journal of Applied Physics, 58 (2019), 045503	Dislocation analysis of homoepitaxial diamond (001) film by x-ray topography	1703009R 1711120R 1802001A
S.Shikata	関西学院大学	Japanese Journal of Applied Physics, 57 (2018), 111301	Precise measurements of diamond lattice constant	1610088R
阪東恭子	産業技術総合研究所	Bulletin of the Chemical Society of Japan, 91 (2018), 1731–1738	Photoluminescent Properties and Local Structure of Tb Doped Fibrous Alumina	1411125F 1511110F 1610133F
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Yogesh Kumar Maurya	九州大学大学院	J. Am. Chem. Soc., 140 , 22 (2018), 6883–6892	Ground-State Copper(III) Stabilized by N-Confused/N-Linked Corroles: Synthesis, Characterization, and Redox Reactivity	1802151G
Hiromasa Suo	産業技術総合研究所	Japanese Journal of Applied Physics, 57 (2018), 065501	Evaluation of the increase in threading dislocation during the initial stage of physical vapor transport growth of 4H–SiC	1702007A
Keitaro Eguchi	名古屋大学大学院	The Journal of Physical Chemistry C, 122 (2018), 26054–26060	In Situ Real-Time Measurements for Ambipolar Channel Formation Processes in Organic Double-Layer Field-Effect Transistors of CuPc and F16CuPc	1705033F 1707067F
Shinich Shikata	関西学院大学	Jap.J.Appl.Phys., 57 (2018), 111301	Precise measurements of diamond lattice constant using Bond method	1610088R

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澤田啓二	東北大学多元物質科学研究所	X線分析の進歩, 50 (2019), 248-260	X線吸収分光を用いた特殊鋼製鋼スラグ中のFeおよびCrの化学状態分析	1712138R 1804018R 1807055R 1809076R
J. R. Stellhorn	熊本大学	AIP Conference Proceedings, 2054 (2019), 050012-1-7	Anomalous x-ray scattering experiments for disordered materials at the SAGA Light Source	1706046F 1802007A
Noritake Isomura	株式会社豊田中央研究所	Journal of Synchrotron Radiation, 26 (2019),	Distinguishing nitrogen-containing sites in SiO ₂ /4H-SiC(0001) after nitric oxide annealing by X-ray absorption spectroscopy	1706043G 1801149G
Shohei Hayashi	産業技術総合研究所	Japanese Journal of Applied Physics, 58 (2019), 011005	Structural analysis of interfacial dislocations and expanded single Shockley-type stacking faults in forward-current degradation of 4H-SiC p-i-n diodes	1702007A
Hiromasa Suo	産業技術総合研究所	Japanese Journal of Applied Physics, 58 (2019), 021001	Observation of multilayer Shockley-type stacking fault formation during process of epitaxial growth on highly nitrogen-doped 4H-SiC substrate	1702007A
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